

Enhancement Mode N-Channel Power MOSFET

 $TO-252/NMOS/100V/\pm20V/1.7V/75A/7.2m\Omega$

Rev_{0.1}





100V, 7.2mΩ, 75A, Single N-Channel

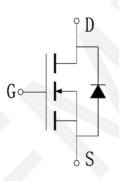
1.Features

- 100V MOSFET technology
- ◆ Low on-state resistance
- Fast switching
- ♦ Vgs±20V
- ◆ 100% RG Tested
- ◆ 100% UIS Tested

- Power Switching Application
- ◆ Load Switching



Pin Description



Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WX070N10KD	070N10	TO-252	2,500	25,000

4Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units	
Drain to Source Voltage	$V_{ extsf{DSS}}$	100	V	
Gate to Source Voltage	V_{GSS}	±20	V	
Drain Current (DC)	I _D	I _D 75		
Drain Current (Pulse), PW≤300μs	I _{DP}	300	А	
Total Dissipation	P_{D}	32	W	
Avalanche Energy, Single Pulsed	E _{AS}	90	mJ	
Junction Temperature	TJ	150	°C	
Storage Temperature	T_{stg}	-55 to +150	°C	

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit	
Junction to Ambient	$R_{ hetaJA}$	55	°C/W	
Junction to case	R _{eJC}	3.9	°C/W	

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

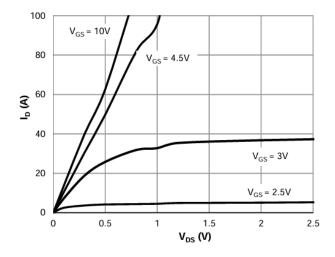
6.Electrical Characteristics at Ta=25°C (Note 3)

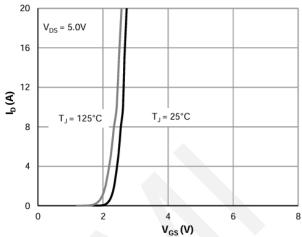
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A, V_{GS} = 0 V$	100	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} =100V, V _{GS} = 0V	ı	-	1	μΑ
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 20V$, $V_{DS} = 0V$	-	-	±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{DS}=250\mu A$	1.2	1.7	2.4	V
Static Drain to Source On-State	В	I _D =20A, V _{GS} = 10V	1	7.2	9.0	mΩ
Resistance	$R_{DS(on)}$	I _D =15A, V _{GS} = 4.5V	-	9.4	11	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V,	-	1872	-	pF
Output Capacitance	C _{oss}	V _{DS} =50V,	1	731	-	pF
Reverse Transfer Capacitance	C _{rss}	Frequency=1.0MHz	-	22	-	pF
Turn-ON Delay Time	t _{d(on)}		-	10	-	ns
Rise Time	t _r	$V_{DD} = 50 \text{V}, V_{GS} = 10 \text{V},$	-	20	-	ns
Turn-OFF Delay Time	$t_{d(off)}$	$R_{GEN} = 3\Omega$, $R_L = 2.5\Omega$	-	40	-	ns
Fall Time	t _f		-	54	-	ns
	Q_g	$V_{DS} = 50V,$ $V_{GS} = 0 \text{ to } 10V,$ $I_{D} = 20A$	-	33	-	nC
Total Gate Charge	Q _{gs}			6	-	nC
	Q_{gd}		-	7	-	nC
Diode Forward Voltage	V _{FSD}	I _S =20A, V _{GS} = 0	-	-	1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

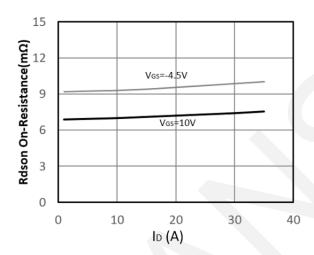


7. Typical electrical and thermal characteristics

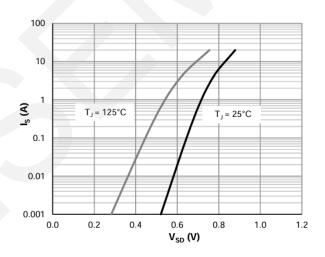




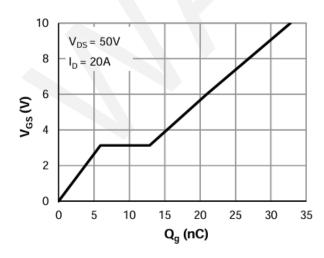
Output Characteristics



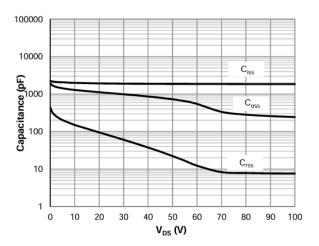
Typical Transfer Characteristics



On-resistance vs. Drain Current



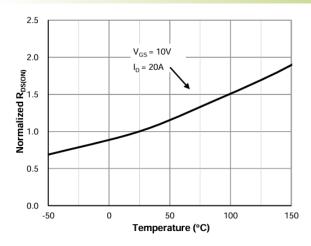
Body Diode Characteristics

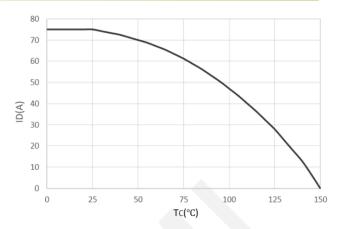


Gate Charge Characteristics

Capacitance Characteristics



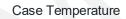


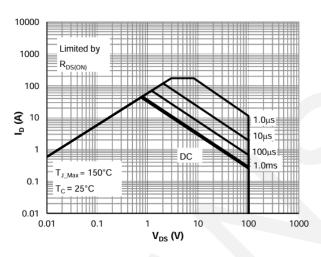


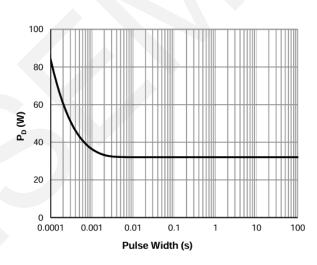
Normalized on Resistance vs.

Maximum Continuous Drain Current vs.

Junction Temperature

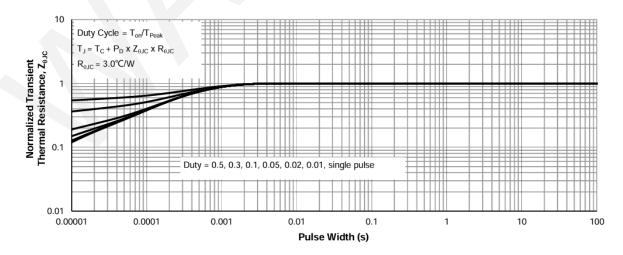






Maximum Safe Operating Area

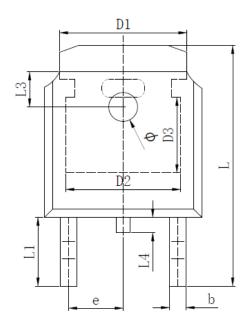
Single Pulse Power Rating, Junction-to-Case

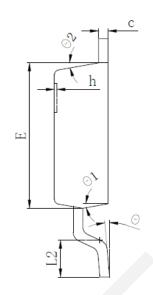


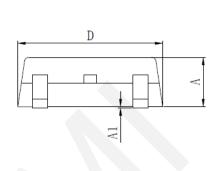
Normalized Maximum Transient Thermal Impedance



8.Package Dimensions







SYMBOL	MILLIMETER			
	MIN	Тур.	MAX	
A	2. 200	2. 300	2. 400	
A1	0.000		0. 127	
b	0.640	0.690	0.740	
c(电镀后)	0. 460	0. 520	0. 580	
D	6. 500	6. 600	6. 700	
D1	5.334 REF			
D2		4.826 REF		
D3		3.166 REF		
E	6. 000	6. 100	6. 200	
е		2.286 TYP		
h	0.000	0.100	0. 200	
L	9. 900	10. 100	10. 300	
L1	2.888 REF			
L2	1. 400	1.550	1. 700	
L3	1.600 REF			
L4	0.600	0.800	1.000	
ф	1. 100	1. 200	1. 300	
θ	0°		8°	
θ1	9° TYP			
θ2		9° TYP		



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